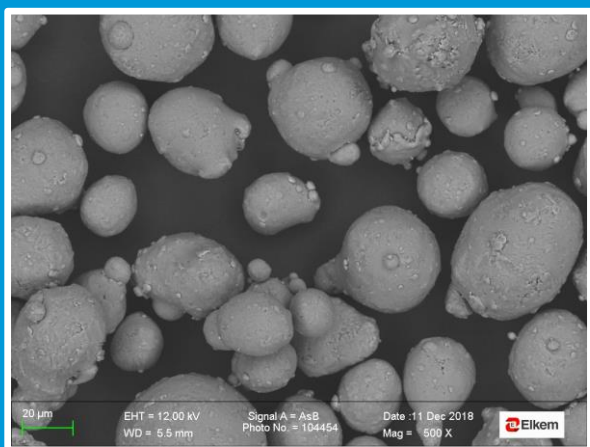
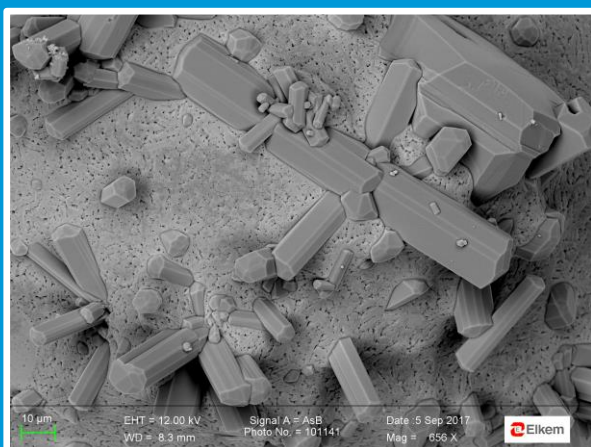


A SEM (Scanning Electron Microscope) is utilised in almost every material challenge, whether its development work, troubleshooting or documentation of microstructure and chemistry. Our SEM is an important tool in research and development and its possibilities are almost endless within materials characterisation

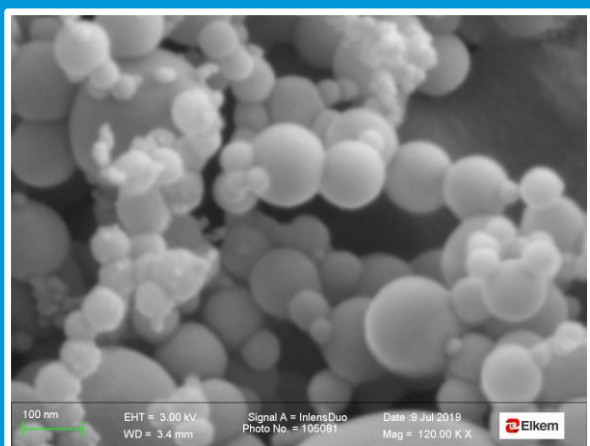
EXAMPLES



Studying size and morphology of gas atomised particles



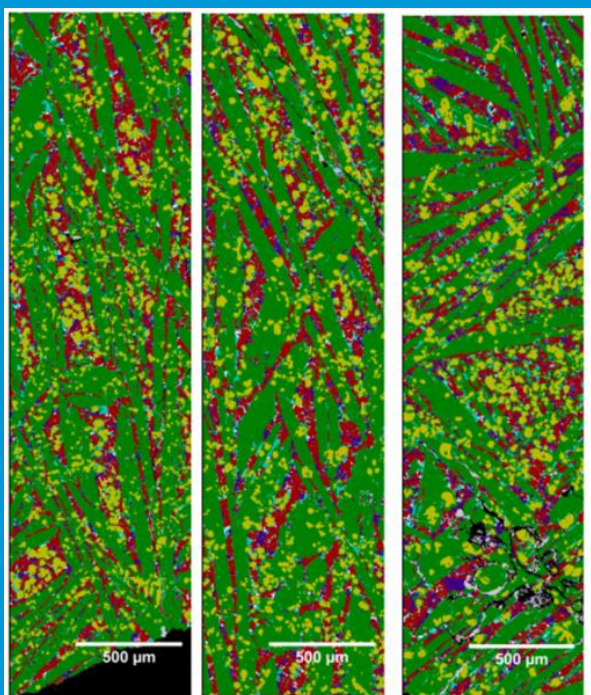
Examine growth of SiC (Carbide) and Si₃N₄ (Nitride) crystals on a substrate



Nano sized particles at 120 000X



Mapping of Aluminium, Silicon and Sulphur in a crushed mineral



AMICS. Large scale mapping of a Ferro Silicon Magnesium alloy (FSM)



CONTACT

Anders H. Amundsen
Manager, Materials Characterisation Lab,
Elkem Technology
etlab@elkem.no
Mobile : +47 90958981

